April 2000 PRELIMINARY

FDS6609A

FAIRCHILD

SEMICONDUCTOR

P-Channel Logic Level PowerTrench[®] MOSFET

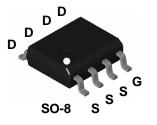
General Description

This P-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

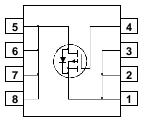
Applications

- DC/DC converter
- Load switch
- Motor Drive



Features

- -6.3 A, -30 V. $R_{DS(ON)} = 0.032 \Omega @V_{GS} = -10 V$ $R_{DS(ON)} = 0.05 \Omega @V_{GS} = -4.5 V$
- Low gate charge
- Fast switching speed
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol		Parameter	Ratings	Units	
V _{DSS}	Drain-Source	Voltage		-30	V
V _{GSS}	Gate-Source	Voltage	±20	V	
b	Drain Current	 Continuous 	(Note 1a)	-6.3	A
		– Pulsed		-40	
P _D	Power Dissipa	ation for Single Operation	ation (Note 1a)	2.5	W
			(Note 1b)	1.2	
			(Note 1c)	1.0	
T _J , T _{STG}	Operating and	Storage Junction Te	emperature Range	-55 to +150	
Therma	I Characte	ristics			
$R_{\theta JA}$	Thermal Resis	nal Resistance, Junction-to-Ambient (Note 1a)		50	°C/W
R _{0JC}	Thermal Resistance, Junction-to-Case (Note 1)		Case (Note 1)	25	°C/W
Packag	e Marking	and Ordering	g Information		
Device Marking		Device	Reel Size	Tape width	Quantity
FDS6609A		FDS6609A	13"	12mm	2500 units

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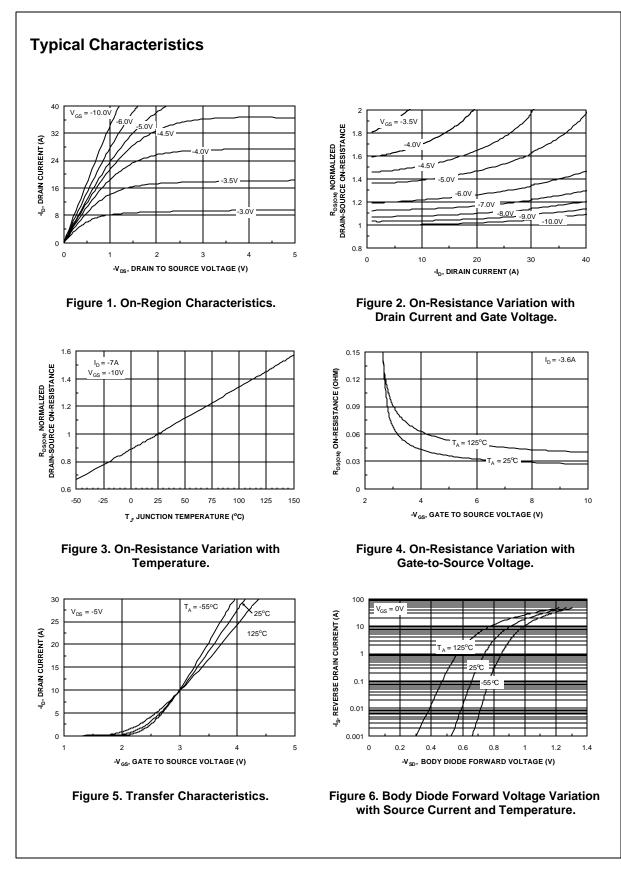
· · · · · · · · · · · · · · · · · · ·	Test Conditions	Min	Тур	Мах	Units
racteristics					
Drain–Source Breakdown Voltage	$V_{GS} = 0 V, I_D = -250 \mu A$	-30			V
Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-22		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = -24 V$, $V_{GS} = 0 V$			-1	μA
Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
Gate-Body Leakage, Reverse	$V_{GS} = -20 V$ $V_{DS} = 0 V$			-100	nA
acteristics (Note 2)					
, ,	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$	-1	-1.5	-3	V
Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu$ A, Referenced to 25°C		4		mV/°C
Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{GS} = -10 \; V, & l_D = -7.0 \; A \\ V_{GS} = -4.5 \; V, & l_D = -5.5 \; A \\ V_{GS} = -10 \; V, \; l_D = -7.0 A, \; T_J {=} 125^\circ C \end{array} $		0.027 0.04 0.04	0.032 0.05 0.54	Ω
On–State Drain Current	$V_{GS} = -10 V$, $V_{DS} = -5 V$	-20			Α
Forward Transconductance			14.5		S
Characteristics					
Input Capacitance	$V_{DS} = -15 V$. $V_{CS} = 0 V$.		930		pF
Output Capacitance	f = 1.0 MHz		278		pF
Reverse Transfer Capacitance			114		pF
			12	21	ns
Turn-On Rise Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$		11	20	ns
Turn–Off Delay Time	-		33	52	ns
Turn–Off Fall Time	-		13	23	ns
Total Gate Charge	$V_{DS} = -15 V$. $I_D = -7.2 A$.		18	29	nC
Gate–Source Charge	$V_{GS} = -10 V$		2.5		nC
Gate–Drain Charge			4.1		nC
ource Diode Characteristics	and Maximum Ratings		1	I	
				-2.1	А
Maximum Continuous Drain–Source					
	Zero Gate Voltage Drain Current Gate–Body Leakage, Forward Gate–Body Leakage, Reverse acteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain–Source On–Resistance On–State Drain Current Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge Gate–Source Charge	Zero Gate Voltage Drain Current $V_{DS} = -24 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$ acteristics(Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $b = -250 \mu\text{A}$ Gate Threshold Voltage $b = -250 \mu\text{A}$, Referenced to 25°C Temperature Coefficient $b = -250 \mu\text{A}$, Referenced to 25°C Static Drain-Source $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $On-Resistance$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $Privard Transconductance$ $V_{DS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $Privard Transconductance$ $V_{DS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $Privard Transconductance$ $V_{DS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $Privard Transconductance$ $V_{DS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ $Privard Transconductance$ $V_{DS} = -10 \text{ V}$, $b = -1.0 \text{ A}$ $Privard Transfer Capacitance$ $Privard Transfer Transfer Capacitance$ $Privard Transfer Capacitance$ P	Zero Gate Voltage Drain Current $V_{DS} = -24 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$ acteristics (Note 2)(Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $b = -250 \mu \text{ A}$, -1 Gate Threshold Voltage $b = -250 \mu \text{ A}$, Referenced to 25°C Temperature Coefficient $b = -7.0 \text{ A}$ Static Drain-Source $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ On-Resistance $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ VGS = -10 V, $b = -7.0 \text{ A}$ $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ On-State Drain Current $V_{GS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ Porward Transconductance $V_{DS} = -10 \text{ V}$, $b = -7.0 \text{ A}$ CharacteristicsInput CapacitanceInput Capacitance $V_{DS} = -15 \text{ V}$, $V_{GS} = 0 \text{ V}$,Output Capacitance $V_{DD} = -15 \text{ V}$, $b = -1 \text{ A}$,Turn-On Delay Time $V_{DD} = -15 \text{ V}$, $B = -1 \text{ A}$,Turn-On Rise Time $V_{CS} = -10 \text{ V}$, $R_{GEN} = 6 \Omega$ Turn-Off Delay Time $V_{DS} = -15 \text{ V}$, $b = -7.2 \text{ A}$,Gate-Source Charge $V_{CS} = -10 \text{ V}$	$ \begin{array}{ c c c c c } \hline Zero Gate Voltage Drain Current & V_{DS} = -24 V, & V_{GS} = 0 V & \\ \hline Gate-Body Leakage, Forward & V_{GS} = 20 V, & V_{DS} = 0 V & \\ \hline Gate-Body Leakage, Reverse & V_{GS} = -20 V & V_{DS} = 0 V & \\ \hline acteristics (Note 2) & \\ \hline Gate Threshold Voltage & V_{DS} = V_{GS}, b = -250 \ \mu\text{A} & -1 & -1.5 & \\ \hline Gate Threshold Voltage & b = -250 \ \mu\text{A}, Referenced to 25^{\circ}\text{C} & 4 & \\ \hline Static Drain-Source & V_{GS} = -10 V, & b = -7.0 \text{ A} & 0.027 & \\ \hline On-Resistance & V_{GS} = -10 V, & b = -7.0 \text{ A} & 0.04 & \\ \hline On-State Drain Current & V_{GS} = -10 V, & b = -7.0 \text{ A} & -10 & \\ \hline Forward Transconductance & V_{DS} = -10 V, & b = -7.0 \text{ A} & 14.5 & \\ \hline Characteristics & \\ \hline Input Capacitance & V_{DS} = -10 V, & b = -7.0 \text{ A} & 14.5 & \\ \hline Characteristics & \\ \hline Input Capacitance & V_{DS} = -15 V, & V_{GS} = 0 V, & 930 & \\ \hline Output Capacitance & V_{DS} = -15 V, & V_{GS} = 0 V, & 930 & \\ \hline Output Capacitance & V_{DD} = -15 V, & b = -1 \text{ A}, & 114 & \\ \hline 10 & Characteristics & (Note 2) & \\ \hline Turm-On Delay Time & V_{DD} = -15 V, & b = -1 \text{ A}, & 112 & \\ \hline Turm-Of Delay Time & V_{DS} = -10 V, & B = -1 \text{ A}, & 112 & \\ \hline Turm-Of Teal Time & & \\ \hline Turm-Of Fall Time & & \\ \hline Turm-Of Sec & & \\ \hline Turm-Of S$	$ \begin{array}{ c c c c c c } \hline Zero Gate Voltage Drain Current & V_{DS} = -24 V, & V_{GS} = 0 V & & & -1 \\ \hline Gate-Body Leakage, Forward & V_{GS} = 20 V, & V_{DS} = 0 V & & & 100 \\ \hline Gate-Body Leakage, Reverse & V_{GS} = -20 V & V_{DS} = 0 V & & & -100 \\ \hline Gate-Body Leakage, Reverse & V_{GS} = -20 V & V_{DS} = 0 V & & & -100 \\ \hline acteristics & (Note 2) & & & & & & & & & & & & & & & & & & $

Scale 1 : 1 on letter size paper

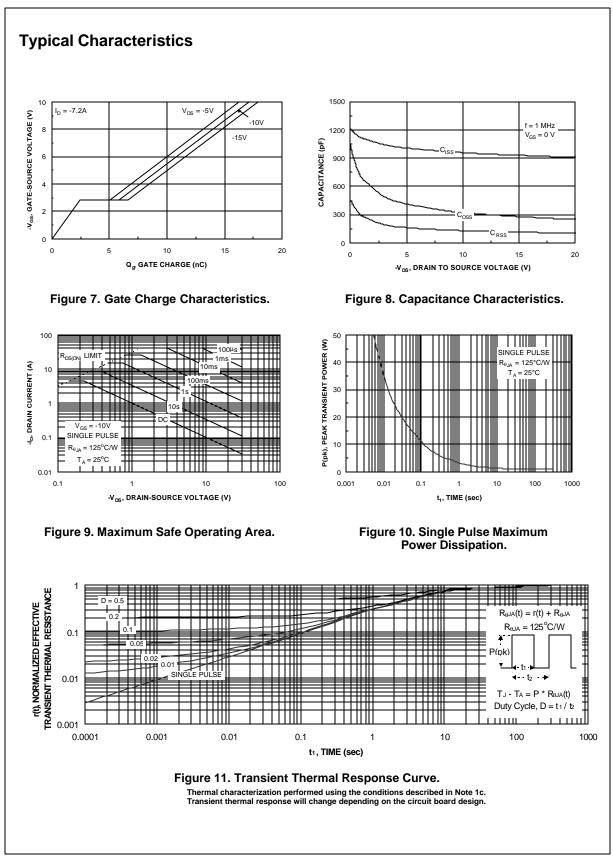
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2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

FDS6609A Rev B(W)

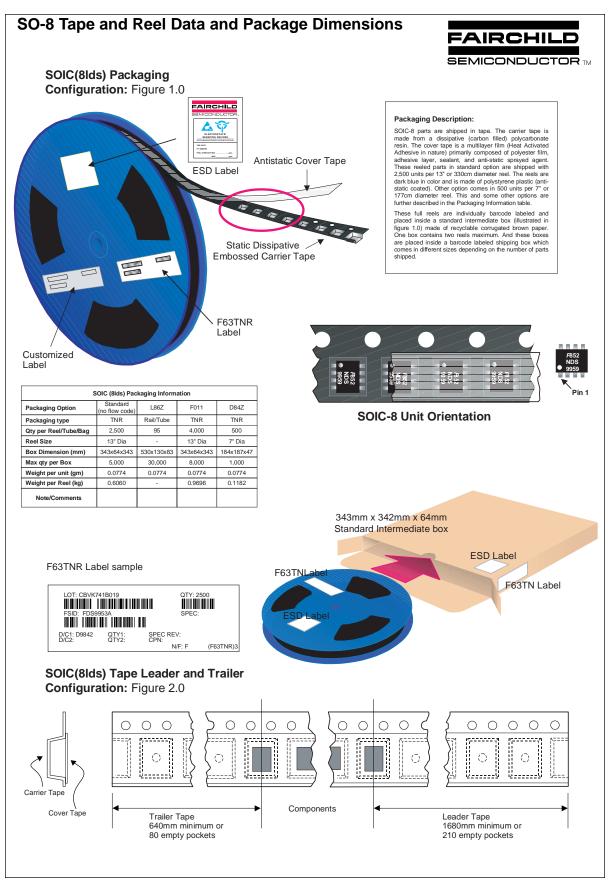


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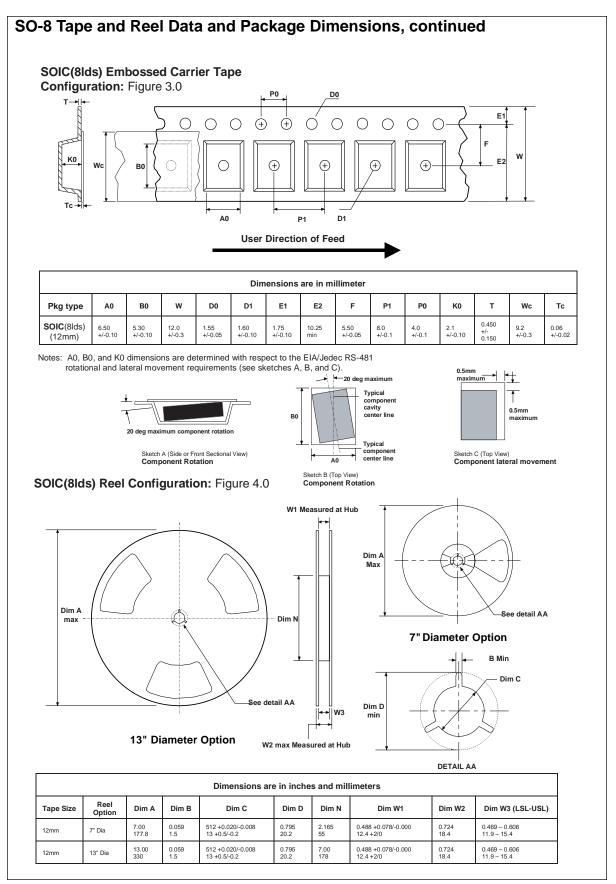


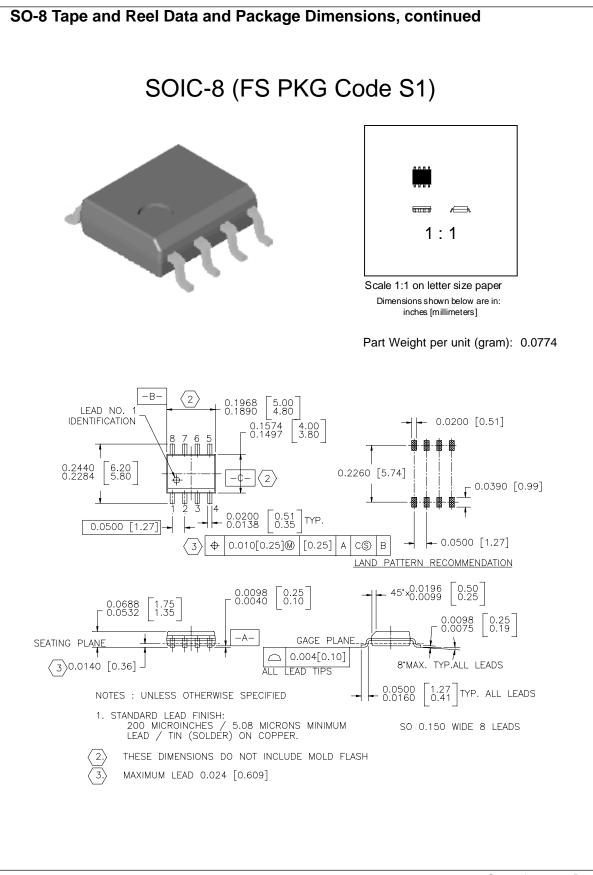
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July 1999, Rev. B





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